

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L4	10	714/37.ccls. and @ad<="20011023" and @pd>="20050111"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/18 12:10
L5	8	714/39.ccls. and @ad<="20011023" and @pd>="20050111"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/18 12:12
L6	6	714/45.ccls. and @ad<="20011023" and @pd>="20050111"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/18 12:17
L7	11	714/46.ccls. and @ad<="20011023" and @pd>="20050111"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/18 12:22
L8	24	714/48.ccls. and @ad<="20011023" and @pd>="20050111"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/18 12:34
L9	4	714/55.ccls. and @ad<="20011023" and @pd>="20050111"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/18 12:35
L10	12	714/704.ccls. and @ad<="20011023" and @pd>="20050111"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/18 12:42
L11	5	714/736.ccls. and @ad<="20011023" and @pd>="20050111"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/18 12:44
L12	2	714/745.ccls. and @ad<="20011023" and @pd>="20050111"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/18 12:44

S1	6	(UCHIYAMA-HIROTO).in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/23 10:00
S2	50	((714/37.ccls. and @ad<="20011023") (714/39.ccls. and @ad<="20011023") (714/45. ccls. and @ad<="20011023") (714/46.ccls. and @ad<="20011023") (714/48.ccls. and @ad<="20011023") (714/704.ccls. and @ad<="20011023") (714/736. ccls. and @ad<="20011023") (714/745.ccls. and @ad<="20011023")) and (("IC" or "integrated circuit") adj tester)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/23 14:50
S3	333	((("IC" or "integrated circuit") adj tester) and (sample or sampling)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/26 08:34
S4	286	((("IC" or "integrated circuit") adj tester) and (sample or sampling)) and @ad<="20011023"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/26 08:40
S5	3326	("IC" or "integrated circuit") adj tester	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/11 14:36
S6	3	((("IC" or "integrated circuit") adj tester) and (mu and sigma)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/12 12:25
S7	22	((("IC" or "integrated circuit") adj tester) and ((standard adj deviation) and (average or mean))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/26 14:10
S8	904	714/704.ccls. and @ad<="20011023"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/26 15:09

S9	33	(714/704.ccls. and @ad<="20011023") and tester	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/11 08:40
S10	312	714/37.ccls. and @ad<="20011023"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/18 12:07
S11	298	714/39.ccls. and @ad<="20011023"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/28 08:59
S12	255	714/57.ccls. and @ad<="20011023"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/11 08:49
S13	321	714/45.ccls. and @ad<="20011023"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/28 08:59
S14	376	714/46.ccls. and @ad<="20011023"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/28 08:59
S15	601	714/48.ccls. and @ad<="20011023"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/28 08:59
S16	134	((714/37.ccls. and @ad<="20011023") (714/39.ccls. and @ad<="20011023") (714/45.ccls. and @ad<="20011023") (714/46.ccls. and @ad<="20011023") (714/48.ccls. and @ad<="20011023")) and tester	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/11 08:45
S17	776	714/736.ccls. and @ad<="20011023"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/28 09:02

S18	129	714/745.ccls. and @ad<="20011023"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/07/28 09:02
S19	260	((714/736.ccls. and @ad<="20011023") (714/745. ccls. and @ad<="20011023")) and tester	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/11 08:51
S20	4	(714/704.ccls. and @ad<="20011023") and tester and @pd>="20040728"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/11 08:40
S21	5	((714/37.ccls. and @ad<="20011023") (714/39.ccls. and @ad<="20011023") (714/45. ccls. and @ad<="20011023") (714/46.ccls. and @ad<="20011023") (714/48.ccls. and @ad<="20011023")) and tester and @pd>="20040728"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/11 08:45
S22	8	714/57.ccls. and @ad<="20011023" and @pd>="20040728"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/11 08:49
S23	2	((714/736.ccls. and @ad<="20011023") (714/745. ccls. and @ad<="20011023")) and tester and @pd>="20040728"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/11 08:52
S24	3442	("IC" or "integrated circuit") adj tester	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/11 14:36
S25	2	S24 and alarm adj display	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/11 14:37
S27	0	".mu.+3.sigma."	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/12 12:23

S28	24	(("IC" or "integrated circuit") adj tester) and ("mean" or "average") and ("standard deviation")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/12 12:26
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